
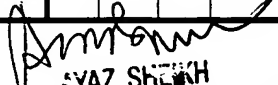



<b>Issue Classification</b> 	<b>Application/Control No.</b> 10/004,019	<b>Applicant(s)/Patent under Reexamination</b> TOH ET AL.
	<b>Examiner</b> Shin-Hon Chen	<b>Art Unit</b> 2131

ISSUE CLASSIFICATION														
ORIGINAL					INTERNATIONAL CLASSIFICATION									
CLASS		SUBCLASS			CLAIMED					NON-CLAIMED				
713		156			H	04	L	9	/00	G	06	F	15	/16
CROSS REFERENCES					H	04	L	9	/30	H	04	K	1	/00
CLASS	SUBCLASS (ONE SUBCLASS PER BLOCK)													
709	205								/					/
380	30								/					/
713	178								/					/
									/					/
									/					/

S.C. Shin-Hon Chen 3/8/07 (Assistant Examiner) (Date)	 AYAZ SHEKH SUPERVISORY PATENT EXAMINER TECHNOLOGY CENTER 2100 (Primary Examiner) (Date) 2/17/08	Total Claims Allowed: 57
 (Legal Instruments Examiner) (Date) 3/14/07	O.G. Print Claim(s) 1	O.G. Print Fig. 4

<input checked="" type="checkbox"/> Claims renumbered in the same order as presented by applicant					<input type="checkbox"/> CPA		<input type="checkbox"/> T.D.		<input type="checkbox"/> R.1.47		
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	7		37		67		97		127		157
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	9		39		69		99		129		159
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